

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: David C. Newbury, et al. : Confirmation No.: 2638
Serial No.: 10/791,130 : Art Unit: 2829
Filed: 3/1/2004 : Examiner: Jermele M.
Hollington
For: TEST STRUCTURE AND :
METHOD FOR FAILURE
ANALYSIS OF SMALL
CONTACTS IN
INTEGRATED CIRCUIT
TECHNOLOGY
DEVELOPMENT

Mail Stop AF
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

**RESPONSE AFTER FINAL REJECTION
UNDER 37 C.F.R. §1.116**

Sir:

The following Remarks are submitted under 37 C.F.R. §1.116 in response to the Office Action mailed March 20, 2006, following the format set forth under 37 CFR §1.121. After this introductory section there are Remarks, starting on a separate page.

Reconsideration of the rejections is respectfully requested.